

Surface chemical analysis — Auger electron spectroscopy and X-ray photoelectron spectroscopy — Determination of lateral resolution, analysis area, and sample area viewed by the analyser

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National foreword

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Summary of pages

This document comprises a front cover, an inside front cover, the ISO/TR title page, pages ii to v, a blank page, pages 1 to 17 and a back cover.
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**Surface chemical analysis — Auger
electron spectroscopy and X-ray
photoelectron spectroscopy —
Determination of lateral resolution,
analysis area, and sample area viewed by
the analyser**

*Analyse chimique des surfaces — Spectroscopie des électrons Auger
et spectroscopie de photo-électrons — Détermination de la résolution
latérale, de l'aire de la surface d'analyse et de l'aire de la surface de
l'échantillon contribuant au signal détecté*



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Foreword

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ISO/TR 19319 was prepared by Technical Committee ISO/TC 201, *Surface chemical analysis*, Subcommittee SC 5, *Auger electron spectroscopy*.

Introduction

This Technical Report is intended to be used as follows:

- a) To provide guidance on the determination of lateral resolution in Auger electron spectroscopy and X-ray photoelectron spectroscopy where measurements are made of Auger electron or X-ray photoelectron peak intensities as a function of position on a sample surface.
- b) To provide guidance on the determination of analysis area in similar applications of Auger electron spectroscopy and X-ray photoelectron spectroscopy.
- c) To provide guidance on the determination of sample area viewed by the analyser in applications of Auger electron spectroscopy and X-ray photoelectron spectroscopy.
- d) To serve as a basis for the development of International Standards for measurements of lateral resolution, analysis area, and sample area viewed by the analyser in Auger electron spectroscopy and X-ray photoelectron spectroscopy.

